

Notice of References Cited	Application/Control No. 10/583,648		Applicant(s)/Patent Under Reexamination GUO ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,064,816 A	05-2000	Parthasarathy et al.	717/109
*	B	US-6,058,396 A	05-2000	Birze et al.	1/1
*	C	US-6,081,665 A	06-2000	Nilsen et al.	717/116
*	D	US-6,138,269 A	10-2000	Ball et al.	717/108
*	E	US-6,151,703 A	11-2000	Crelrier, Regis	717/136
*	F	US-6,289,506 B1	09-2001	Kwong et al.	717/148
*	G	US-6,317,872 B1	11-2001	Gee et al.	717/152
*	H	US-6,381,734 B1	04-2002	Golde et al.	717/165
*	I	US-2002/0108107 A1	08-2002	Darnell et al.	717/153
*	J	US-6,453,463 B1	09-2002	Chaudhry et al.	717/127
*	K	US-6,557,023 B1	04-2003	Taivalsaari, Antero	718/1
*	L	US-2004/0015918 A1	01-2004	Kawahito et al.	717/151
*	M	US-6,681,381 B1	01-2004	Soepenbergen et al.	717/118

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
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NON-PATENT DOCUMENTS

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,694,507 B2	02-2004	Arnold et al.	717/108
*	B	US-2004/0103391 A1	05-2004	Wu et al.	717/122
*	C	US-2004/0205750 A1	10-2004	Neuenhofen, Kay A.	718/001
*	D	US-6,865,730 B1	03-2005	Burke et al.	717/116
*	E	US-6,886,159 B2	04-2005	Onodera, Tamiya	717/165
*	F	US-7,058,929 B2	06-2006	Charnell et al.	717/135
*	G	US-7,200,842 B1	04-2007	Susser et al.	717/159
*	H	US-7,210,122 B2	04-2007	Shuf et al.	717/116
*	I	US-7,266,813 B2	09-2007	Nistler et al.	717/141
*	J	US-7,272,828 B2	09-2007	Wu et al.	717/148
*	K	US-2007/0277021 A1	11-2007	O'Connor et al.	712/208
*	L	US-7,356,802 B2	04-2008	de Sutter et al.	717/108
*	M	US-7,373,639 B2	05-2008	Halstead et al.	717/140

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2009/0064114 A1	03-2009	Bottomley et al.	717/148
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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